Group Art Unit: 2886
Confirmation No.: 3799
Atty. Ref.: F04-018US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Tohru Koike et al.

Appl. No. : 10/575,714

Filed : May 8, 2006

For : METHOD FOR MEASURING A SURFACE PLASMON

RESONANCE AND NOBLE METAL COMPOUND USED FOR THE

SAME

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

SECOND INFORMATION DISCLOSURE STATEMENT

Sir:

The above-identified U.S. patent application relates to Japanese Patent Appl. No. JP2006-077240. An Office Action was issued in connection with the Japanese application on October 6, 2009 and a copy of that Office Action is attached along with an English language translation. The Examiner will note that the Japanese Patent Office cited four non-patent publications and one Japanese reference. All of these references have been listed on the attached copy of Form PTO/SB/08A and copies of all the references are attached. The Japanese patent reference also is accompanied by an English language abstract obtained from the database of the Japanese Patent Office. Additionally, the Japanese language non-patent publication is accompanied by an English language translation.

The Examiner is requested to consider these references during the examination and to make the references of record.

Respectfully submitted,

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